



OIML Certification System (OIML-CS) Implementation Accreditation in Legal Metrology

Legal Metrology Experts

Legal Metrology Experts validated by the OIML-CS Management Committee to participate in Accreditation and Peer Assessments under the OIML-CS

Expert Name	Country	OIML Recommendation																				Assessment Experience						
		R 16	R 21	R 35	R 46	R 49	R 50	R 51	R 60	R 61	R 75	R 76	R 85	R 99	R 106	R 107	R 111	R 117	R 126	R 129	R 134	R 137	R 139	R 148	R 149	ISO/IEC 17020	ISO/IEC 17025	ISO/IEC 17065
CHEN, Yi	AU						✓	✓	✓			✓			✓	✓											✓	
ZAMORA, Mario	AU																	✓										
MATEUS SANCHEZ, Juan Carlos ¹	BR	✓	✓		✓						✓		✓				✓	✓							✓		✓	
COUVREUR, Gulian	CH						✓	✓	✓	✓		✓			✓	✓					✓					✓	✓	
DE HUU, Marc	CH																					✓				✓		
NIEDERHAUSER, Bernhard	CH																		✓							✓		
HU, Manhong	CN						✓	✓		✓		✓				✓					✓							
SHI, Leibing	CN				✓																							
WANG, Jian	CN						✓	✓		✓		✓				✓	✓				✓					✓		
YANG, Jing	CN																	✓										
YANG, Youtao	CN																					✓						
ZHONG, Ruilin	CN						✓	✓		✓		✓				✓	✓				✓							
ZHOU, Shaoyuan	CN				✓																							

1 For EMC tests only

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		R 16	R 21	R 35	R 46	R 49	R 50	R 51	R 60	R 61	R 75	R 76	R 85	R 99	R 106	R 107	R 111	R 117	R 126	R 129	R 134	R 137	R 139	R 148	R 149	ISO/IEC 17020	ISO/IEC 17025	ISO/IEC 17065
BENKOVA, Miroslava	CZ					✓											✓										✓	
BÍLEK, Jindřich	CZ											✓					✓										✓	
KALOUS, Stanislav	CZ																						✓				✓	
KRIZ, Ivan	CZ						✓	✓		✓		✓		✓	✓					✓							✓	
VALENTA, Tomáš	CZ																					✓					✓	✓
KRAMER, Rainer	DE																				✓	✓					✓	
ROSE, Jürgen	DE									✓																✓	✓	✓
JENSEN, Jens Hovgård	DK						✓	✓		✓		✓			✓					✓	✓							
DELETTE, Laetitia	FR																	✓									✓	
LOPEZ, Luc ²	FR		✓					✓		✓	✓	✓					✓											✓
MOREL, Emeric	FR					✓																					✓	
PEREZ, Reuven	IL					✓																					✓	
AGARWAL, Ashutosh	IN		✓			✓	✓	✓	✓	✓		✓					✓							✓	✓		✓	
PIROVANO, Miriam	IT																					✓					✓	✓
SESTINI, Maria Cristina	IT																					✓					✓	✓
ZOTTI, Lucio	IT					✓		✓		✓		✓					✓										✓	✓
AZAMI, Nobuhiko	JP								✓																			
NAGANO, Tomohiro	JP											✓															✓	
OTANI, Satoshi	JP											✓															✓	
TANAKA, Yoshitada	JP								✓																			

2 Limited to assessments of OIML Issuing Authorities

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		R 16	R 21	R 35	R 46	R 49	R 50	R 51	R 60	R 61	R 75	R 76	R 85	R 99	R 106	R 107	R 111	R 117	R 126	R 129	R 134	R 137	R 139	R 148	R 149	ISO/IEC 17020	ISO/IEC 17025	ISO/IEC 17065
BEUMER, Erik	NL					✓					✓		✓					✓					✓				✓	
BOEREBOOM, Hans	NL				✓																							
KOK, Paul	NL		✓				✓	✓		✓		✓		✓					✓	✓	✓						✓	✓
MEIJER, Mathias	NL		✓				✓		✓			✓															✓	✓
ROOIJ, Paul van	NL					✓					✓		✓					✓				✓	✓				✓	
SCHOLTEN, Roy	NL							✓		✓		✓			✓					✓							✓	
SOEKHOE, Satish	NL																	✓				✓	✓				✓	
TJOA, Aldemar	NL				✓	✓		✓			✓	✓	✓					✓		✓		✓					✓	
VERMEUL, Yvo	NL					✓						✓						✓				✓					✓	
YILMAZ, Baris	NL							✓				✓								✓							✓	✓
BOBBALA, Srinivas	NZ											✓						✓									✓	
HATTINGH, Jaco	NZ					✓						✓															✓	
KÄLLGREN, Hakan	SE						✓	✓	✓	✓		✓			✓	✓											✓	✓
GRUM, Matej	SI						✓	✓		✓		✓			✓	✓											✓	✓
PREMUŠ, Aleksander	SI		✓		✓																						✓	✓
KRAL, Stefan	SK					✓																					✓	✓
MAZÚR, Viliam	SK					✓																					✓	
AYDEMİR, Bülent	TR						✓	✓	✓	✓		✓			✓	✓					✓						✓	
KAÇMAZ, Sevda	TR						✓	✓	✓	✓		✓			✓	✓					✓						✓	
GLAS, Gregory	UK						✓	✓		✓		✓			✓	✓					✓						✓	✓
JAMES, Ivor	UK												✓							✓								
Ji, Wei	UK		✓	✓			✓	✓	✓	✓		✓									✓						✓	✓
WARD, Christine	UK			✓								✓					✓	✓									✓	